



FOR IMMEDIATE RELEASE

NON-VISUAL DEFECT INSPECTION CONTINUES TO GAIN MOMENTUM IN SEMICONDUCTOR INDUSTRY AS QCEPT TECHNOLOGIES ANNOUNCES NEW ORDERS AND MID-YEAR UPDATE

Qcept ships three ChemetriQ® NVD inspection systems in past quarter; has tools in production use at three of the top five global chipmakers for logic, memory and analog applications

ATLANTA, Ga. – July 11, 2011 – Qcept Technologies Inc. today announced that its ChemetriQ® non-visual defect (NVD) inspection systems continue to gain momentum in the semiconductor industry, with the company having sold and shipped three ChemetriQ 5000 systems in the past quarter. This includes the [recently announced order](#) with a leading semiconductor equipment supplier as well as a new repeat order for multiple systems from one of the world’s largest semiconductor manufacturers. In addition, Qcept’s ChemetriQ NVD inspection systems are now in production use at three of the top five global semiconductor manufacturers, where they are being used for advanced logic, memory and analog applications.

“As new materials, processes and structures are being introduced at advanced nodes, the surface quality requirements of semiconductor wafers become increasingly stringent and give rise to a growing number of NVDs,” stated Bret Bergman, CEO of Qcept Technologies. “Leading IC manufacturers have recognized that NVD inspection has become an integral part of yield management, as is evident by these latest orders for our ChemetriQ NVD inspection systems. In fact, Qcept has completed ramping up our manufacturing capacity to at least one system per month in order to support the growing demand for our ChemetriQ wafer inspection technology.”

The ChemetriQ 5000 platform provides [rapid, full-wafer, inline detection of NVDs](#)—such as organic and inorganic residues, metallic contaminants and process-induced charging—which can lead to significant yield loss and are undetectable by optical inspection systems. It accomplishes this by employing an innovative, non-destructive technology that detects work function variations on the wafer surface. Enhanced detection algorithms and tighter positional accuracy further augment the performance of the ChemetriQ 5000 to capture a variety of NVDs on both patterned and unpatterned wafers.

About Qcept Technologies Inc.:

Qcept Technologies delivers wafer inspection solutions for non-visual defect (NVD) detection in advanced semiconductor manufacturing. Qcept’s ChemetriQ® platform is being adopted in critical processes for inline, non-contact, full-wafer detection of such NVDs as sub-monolayer organic and metallic residues, process-induced charging, and other undesired surface non-uniformities that cannot be detected by conventional optical inspection equipment. More information can be found at www.qceptech.com.

ChemetriQ is a registered trademark of Qcept Technologies Inc. All other trademarks are the property of their respective owners.

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